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Form PTD 149 (Modified)  FOR PTD 149 (Modified)  FRADE PATENT AND TRADEMARK OFFICE				ATTY DOCKET NO. 285645US3PCT		SERIAL NO. 10/567,034			
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LIST OF REFERENCES CITED BY APPLICANT				Naoki HASHIGUCHI					
				FILING DATE		GROUP			
				February 3, 2006					
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		NG DATE	
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Examiner /Stefan Kruer/					Date Considered 09/27/2006				
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									